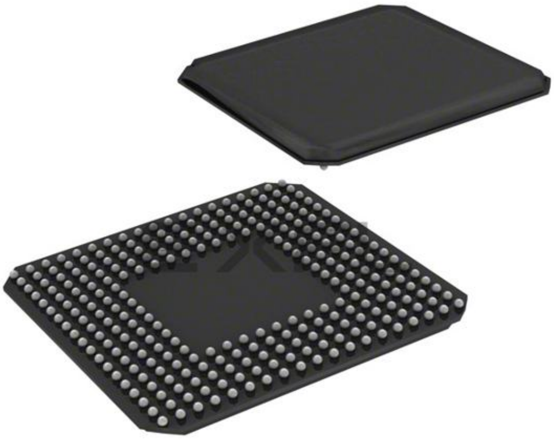
AMD Xilinx - XCS40XL-4CS280C Datasheet



Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	784
Number of Logic Elements/Cells	1862
Total RAM Bits	25088
Number of I/O	224
Number of Gates	40000
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	280-TFBGA, CSPBGA
Supplier Device Package	280-CSBGA (16x16)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs40xl-4cs280c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Spartan and Spartan-XL devices provide system clock rates exceeding 80 MHz and internal performance in excess of 150 MHz. In addition to the conventional benefit of high volume programmable logic solutions, Spartan series FPGAs also offer on-chip edge-triggered single-port and dual-port RAM, clock enables on all flip-flops, fast carry logic, and many other features.

The Spartan/XL families leverage the highly successful XC4000 architecture with many of that family's features and benefits. Technology advancements have been derived from the XC4000XLA process developments.

Logic Functional Description

The Spartan series uses a standard FPGA structure as shown in Figure 1, page 2. The FPGA consists of an array of configurable logic blocks (CLBs) placed in a matrix of routing channels. The input and output of signals is achieved through a set of input/output blocks (IOBs) forming a ring around the CLBs and routing channels.

- CLBs provide the functional elements for implementing the user's logic.
- IOBs provide the interface between the package pins and internal signal lines.
- Routing channels provide paths to interconnect the inputs and outputs of the CLBs and IOBs.

The functionality of each circuit block is customized during configuration by programming internal static memory cells. The values stored in these memory cells determine the logic functions and interconnections implemented in the FPGA.

Configurable Logic Blocks (CLBs)

The CLBs are used to implement most of the logic in an FPGA. The principal CLB elements are shown in the simplified block diagram in Figure 2. There are three look-up tables (LUT) which are used as logic function generators, two flip-flops and two groups of signal steering multiplexers. There are also some more advanced features provided by the CLB which will be covered in the **Advanced Features Description**, page 13.

Function Generators

Two 16 x 1 memory look-up tables (F-LUT and G-LUT) are used to implement 4-input function generators, each offering unrestricted logic implementation of any Boolean function of up to four independent input signals (F1 to F4 or G1 to G4). Using memory look-up tables the propagation delay is independent of the function implemented.

A third 3-input function generator (H-LUT) can implement any Boolean function of its three inputs. Two of these inputs are controlled by programmable multiplexers (see box "A" of Figure 2). These inputs can come from the F-LUT or G-LUT outputs or from CLB inputs. The third input always comes from a CLB input. The CLB can, therefore, implement certain functions of up to nine inputs, like parity checking. The three LUTs in the CLB can also be combined to do any arbitrarily defined Boolean function of five inputs.

Table 2: **CLB Storage Element Functionality**

Mode	CK	EC	SR	D	Q
Power-Up or GSR	X	X	X	X	SR
Flip-Flop Operation	X	X	1	X	SR
	↑	1*	0*	D	D
	0	X	0*	X	Q
Latch Operation (Spartan-XL)	1	1*	0*	X	Q
	0	1*	0*	D	D
Both	X	0	0*	X	Q

Legend:

X	Don't care
↑	Rising edge (clock not inverted).
SR	Set or Reset value. Reset is default.
0*	Input is Low or unconnected (default value)
1*	Input is High or unconnected (default value)

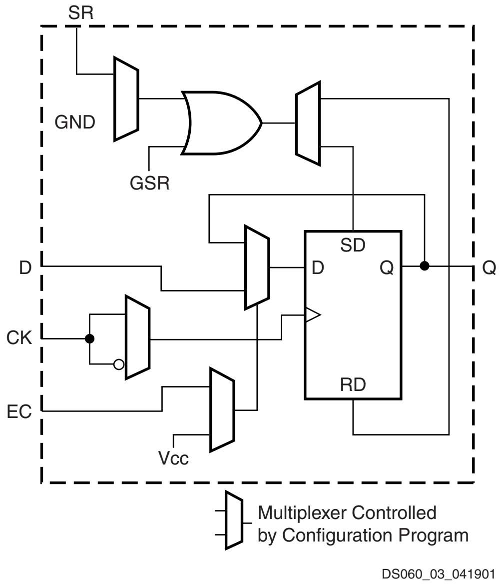


Figure 3: **CLB Flip-Flop Functional Block Diagram**

Clock Input

Each flip-flop can be triggered on either the rising or falling clock edge. The CLB clock line is shared by both flip-flops. However, the clock is individually invertible for each flip-flop (see CK path in Figure 3). Any inverter placed on the clock line in the design is automatically absorbed into the CLB.

Clock Enable

The clock enable line (EC) is active High. The EC line is shared by both flip-flops in a CLB. If either one is left disconnected, the clock enable for that flip-flop defaults to the active state. EC is not invertible within the CLB. The clock enable is synchronous to the clock and must satisfy the setup and hold timing specified for the device.

Set/Reset

The set/reset line (SR) is an asynchronous active High control of the flip-flop. SR can be configured as either set or reset at each flip-flop. This configuration option determines the state in which each flip-flop becomes operational after configuration. It also determines the effect of a GSR pulse during normal operation, and the effect of a pulse on the SR line of the CLB. The SR line is shared by both flip-flops. If SR is not specified for a flip-flop the set/reset for that flip-flop defaults to the inactive state. SR is not invertible within the CLB.

CLB Signal Flow Control

In addition to the H-LUT input control multiplexers (shown in box "A" of Figure 2, page 4) there are signal flow control multiplexers (shown in box "B" of Figure 2) which select the signals which drive the flip-flop inputs and the combinatorial CLB outputs (X and Y).

Each flip-flop input is driven from a 4:1 multiplexer which selects among the three LUT outputs and DIN as the data source.

Each combinatorial output is driven from a 2:1 multiplexer which selects between two of the LUT outputs. The X output can be driven from the F-LUT or H-LUT, the Y output from G-LUT or H-LUT.

Control Signals

There are four signal control multiplexers on the input of the CLB. These multiplexers allow the internal CLB control signals (H1, DIN, SR, and EC in Figure 2 and Figure 4) to be driven from any of the four general control inputs (C1-C4 in Figure 4) into the CLB. Any of these inputs can drive any of the four internal control signals.

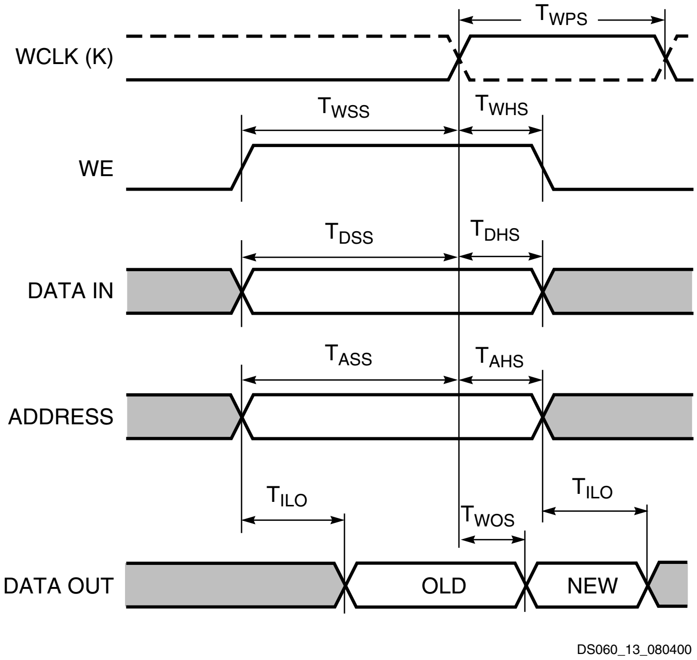


Figure 13: **Data Write and Access Timing for RAM**

WCLK can be configured as active on either the rising edge (default) or the falling edge. While the WCLK input to the RAM accepts the same signal as the clock input to the associated CLB's flip-flops, the sense of this WCLK input can be inverted with respect to the sense of the flip-flop clock inputs. Consequently, within the same CLB, data at the RAM SPO line can be stored in a flip-flop with either the same or the inverse clock polarity used to write data to the RAM.

The WE input is active High and cannot be inverted within the CLB.

Allowing for settling time, the data on the SPO output reflects the contents of the RAM location currently addressed. When the address changes, following the asynchronous delay T_{ILO}, the data stored at the new address location will appear on SPO. If the data at a particular RAM address is overwritten, after the delay T_{WOS}, the new data will appear on SPO.

Dual-Port Mode

In dual-port mode, the function generators (F-LUT and G-LUT) are used to create a 16 x 1 dual-port memory. Of the two data ports available, one permits read and write operations at the address specified by A[3:0] while the second provides only for read operations at the address specified independently by DPRA[3:0]. As a result, simultaneous read/write operations at different addresses (or even at the same address) are supported.

The functional organization of the 16 x 1 dual-port RAM is shown in Figure 14. The dual-port RAM signals and the

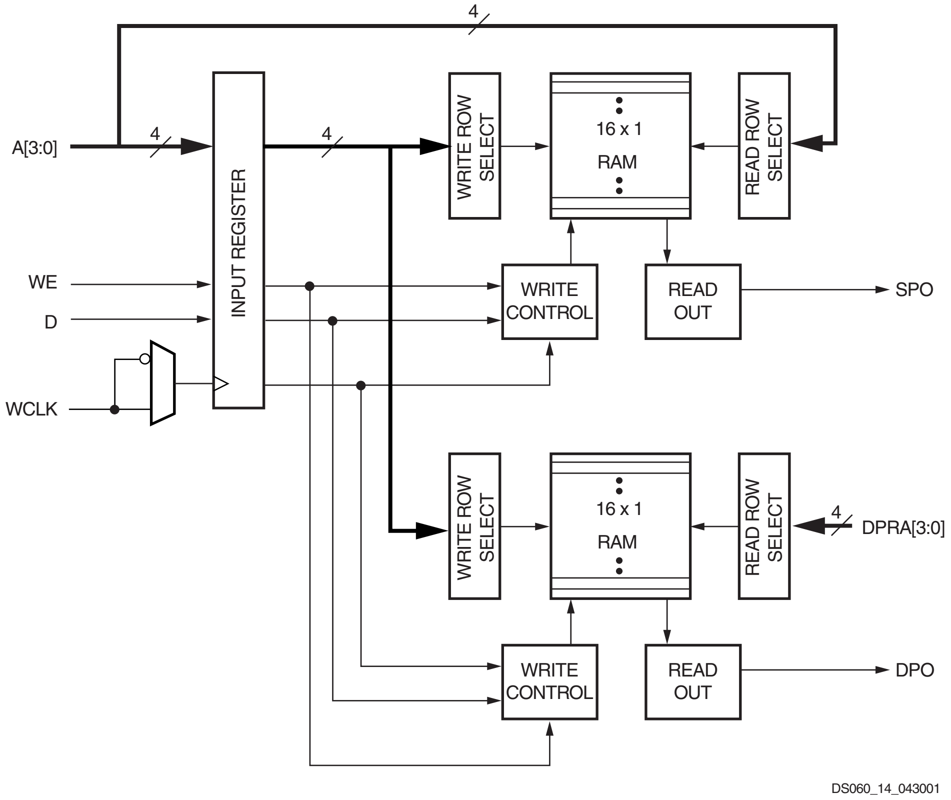


Figure 14: **Logic Diagram for the Dual-Port RAM**

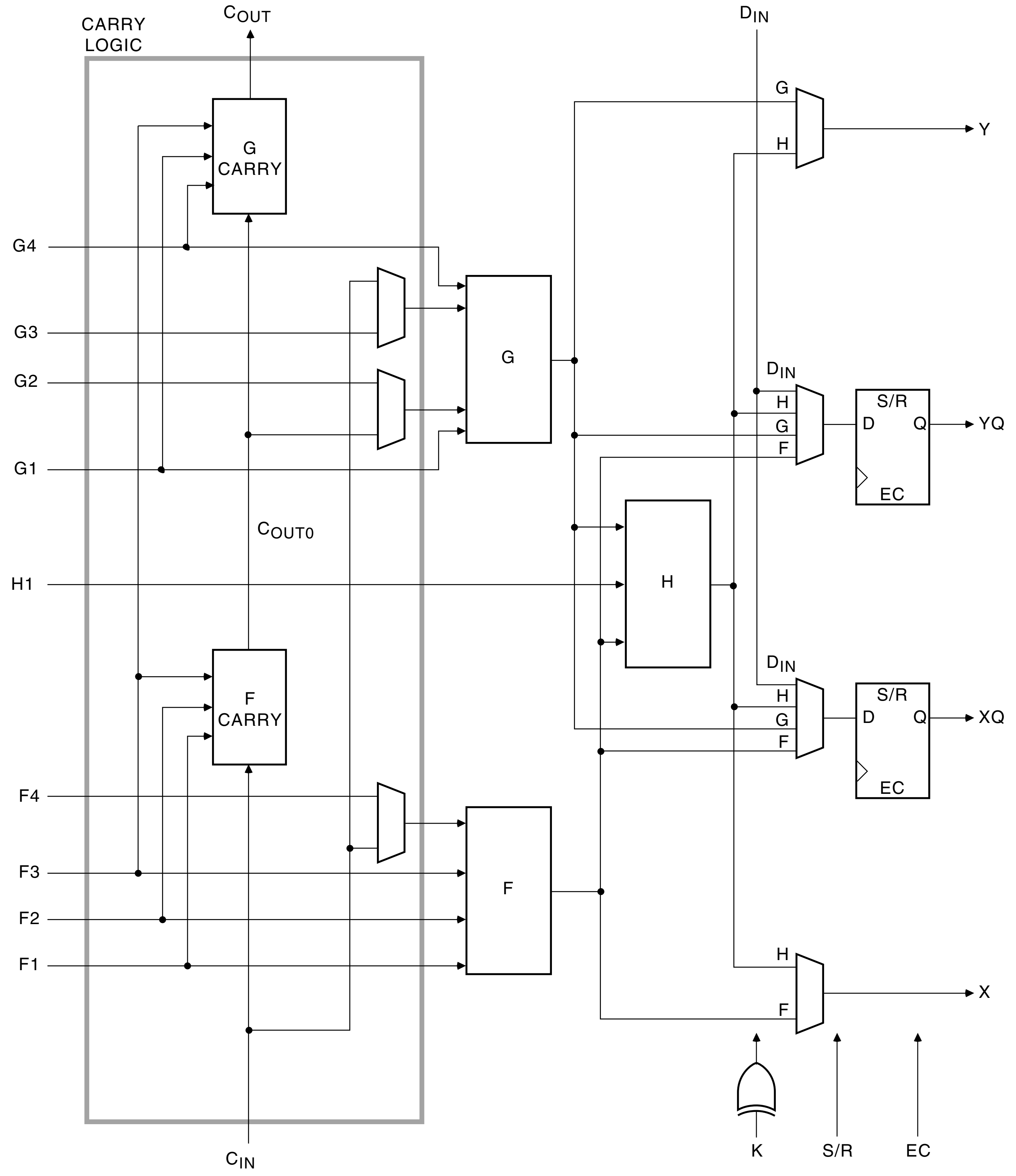


Figure 16: **Fast Carry Logic in Spartan/XL CLB**

On-Chip Oscillator

Spartan/XL devices include an internal oscillator. This oscillator is used to clock the power-on time-out, for configuration memory clearing, and as the source of CCLK in Master configuration mode. The oscillator runs at a nominal 8 MHz frequency that varies with process, V_{CC}, and temperature. The output frequency falls between 4 MHz and 10 MHz.

The oscillator output is optionally available after configuration. Any two of four resynchronized taps of a built-in divider are also available. These taps are at the fourth, ninth, fourteenth and nineteenth bits of the divider. Therefore, if the primary oscillator output is running at the nominal 8 MHz, the user has access to an 8-MHz clock, plus any two of 500 kHz, 16 kHz, 490 Hz and 15 Hz. These frequencies can vary by as much as -50% or +25%.

These signals can be accessed by placing the OSC4 library element in a schematic or in HDL code. The oscillator is automatically disabled after configuration if the OSC4 symbol is not used in the design.

Global Signals: GSR and GTS

Global Set/Reset

A separate Global Set/Reset line, as shown in Figure 3, page 5 for the CLB and Figure 5, page 6 for the IOB, sets or clears each flip-flop during power-up, reconfiguration, or when a dedicated Reset net is driven active. This global net (GSR) does not compete with other routing resources; it uses a dedicated distribution network.

Each flip-flop is configured as either globally set or reset in the same way that the local set/reset (SR) is specified. Therefore, if a flip-flop is set by SR, it is also set by GSR. Similarly, if in reset mode, it is reset by both SR and GSR.

GSR can be driven from any user-programmable pin as a global reset input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GSR pin of the STARTUP symbol. (See Figure 19.) A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the GSR signal. Alternatively, GSR can be driven from any internal node.

Global 3-State

A separate Global 3-state line (GTS) as shown in Figure 6, page 7 forces all FPGA outputs to the high-impedance state, unless boundary scan is enabled and is executing an EXTEST instruction. GTS does not compete with other routing resources; it uses a dedicated distribution network.

GTS can be driven from any user-programmable pin as a global 3-state input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GTS pin of the STARTUP symbol. This is similar to what is shown in Figure 19 for GSR except the IBUF would be connected to GTS. A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global 3-state signal. Alternatively, GTS can be driven from any internal node.

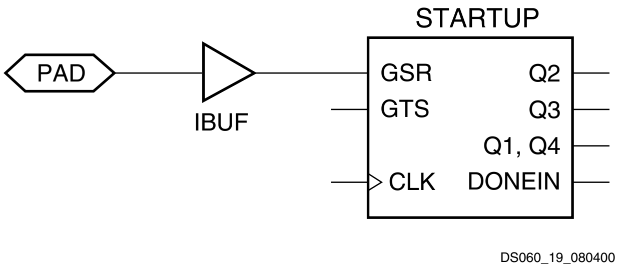


Figure 19: **Symbols for Global Set/Reset**

Boundary Scan

The "bed of nails" has been the traditional method of testing electronic assemblies. This approach has become less appropriate, due to closer pin spacing and more sophisticated assembly methods like surface-mount technology and multi-layer boards. The IEEE Boundary Scan Standard 1149.1 was developed to facilitate board-level testing of electronic assemblies. Design and test engineers can embed a standard test logic structure in their device to achieve high fault coverage for I/O and internal logic. This structure is easily implemented with a four-pin interface on any boundary scan compatible device. IEEE 1149.1-compatible devices may be serial daisy-chained together, connected in parallel, or a combination of the two.

The Spartan and Spartan-XL families implement IEEE 1149.1-compatible BYPASS, PRELOAD/SAMPLE and EXTEST boundary scan instructions. When the boundary scan configuration option is selected, three normal user I/O pins become dedicated inputs for these functions. Another user output pin becomes the dedicated boundary scan output. The details of how to enable this circuitry are covered later in this section.

By exercising these input signals, the user can serially load commands and data into these devices to control the driving of their outputs and to examine their inputs. This method is an improvement over bed-of-nails testing. It avoids the need to over-drive device outputs, and it reduces the user interface to four pins. An optional fifth pin, a reset for the control logic, is described in the standard but is not implemented in the Spartan/XL devices.

The dedicated on-chip logic implementing the IEEE 1149.1 functions includes a 16-state machine, an instruction register and a number of data registers. The functional details can be found in the IEEE 1149.1 specification and are also discussed in the Xilinx application note: "*Boundary Scan in FPGA Devices.*"

Table 12: **Boundary Scan Instructions**

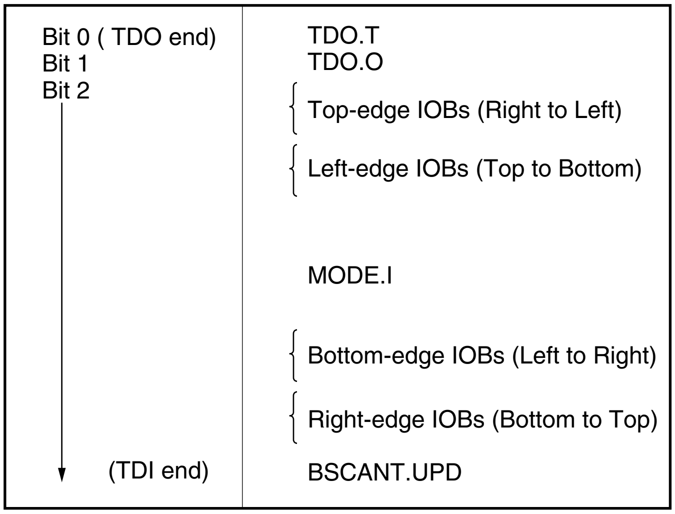
Instruction			Test Selected	TDO Source	I/O Data Source
I2	I1	I0			
0	0	0	EXTEST	DR	DR
0	0	1	SAMPLE/ PRELOAD	DR	Pin/Logic
0	1	0	USER 1	BSCAN. TDO1	User Logic
0	1	1	USER 2	BSCAN. TDO2	User Logic
1	0	0	READBACK	Readback Data	Pin/Logic
1	0	1	CONFIGURE	DOUT	Disabled
1	1	0	IDCODE (Spartan-XL only)	IDCODE Register	-
1	1	1	BYPASS	Bypass Register	-

Bit Sequence

The bit sequence within each IOB is: In, Out, 3-state. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contributes all three bits.

The first two bits in the I/O data register are TDO.T and TDO.O, which can be used for the capture of internal signals. The final bit is BSCANT.UPD, which can be used to drive an internal net. These locations are primarily used by Xilinx for internal testing.

From a cavity-up view of the chip (as shown in the FPGA Editor), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Figure 21. The device-specific pinout tables for the Spartan/XL devices include the boundary scan locations for each IOB pin.



DS060_21_080400

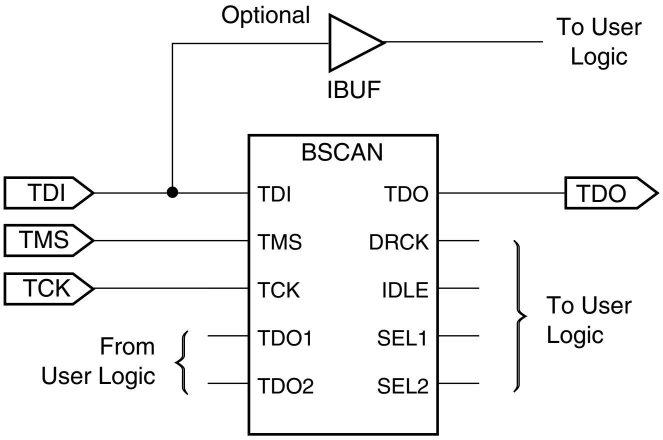
Figure 21: **Boundary Scan Bit Sequence**

BSDL (Boundary Scan Description Language) files for Spartan/XL devices are available on the Xilinx website in the File Download area. Note that the 5V Spartan devices and 3V Spartan-XL devices have different BSDL files.

Including Boundary Scan in a Design

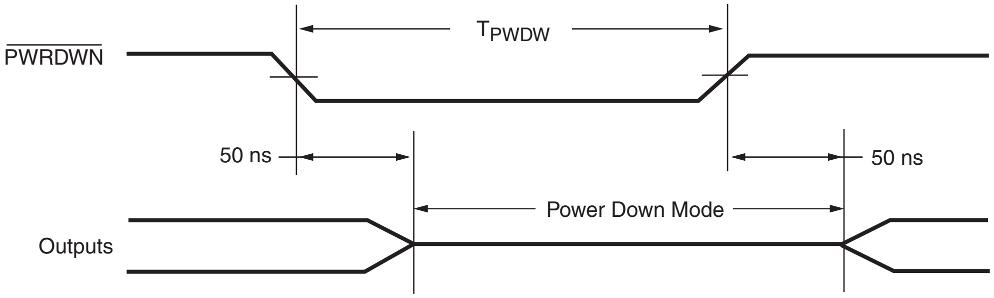
If boundary scan is only to be used during configuration, no special elements need be included in the schematic or HDL code. In this case, the special boundary scan pins TDI, TMS, TCK and TDO can be used for user functions after configuration.

To indicate that boundary scan remain enabled after configuration, place the BSCAN library symbol and connect the TDI, TMS, TCK and TDO pad symbols to the appropriate pins, as shown in Figure 22.



DS060_22_080400

Figure 22: **Boundary Scan Example**



Description	Symbol	Min
Power Down Time	T_{PWD}	50 ns
Power Down Pulse Width	T_{PWDW}	50 ns

DS060_23_041901

Figure 23: **$\overline{\text{PWRDWN}}$ Pulse Timing**

Power-down retains the configuration, but loses all data stored in the device flip-flops. All inputs are interpreted as Low, but the internal combinatorial logic is fully functional. Make sure that the combination of all inputs Low and all flip-flops set or reset in your design will not generate internal oscillations, or create permanent bus contention by activating internal bus drivers with conflicting data onto the same long line.

During configuration, the $\overline{\text{PWRDWN}}$ pin must be High. If the Power Down state is entered before or during configuration, the device will restart configuration once the $\overline{\text{PWRDWN}}$ signal is removed. Note that the configuration pins are affected by Power Down and may not reflect their normal function. If there is an external pull-up resistor on the DONE pin, it will be High during Power Down even if the device is not yet configured. Similarly, if $\overline{\text{PWRDWN}}$ is asserted before configuration is completed, the $\overline{\text{INIT}}$ pin will not indicate status information.

Note that the $\overline{\text{PWRDWN}}$ pin is not part of the Boundary Scan chain. Therefore, the Spartan-XL family has a separate set of BSDL files than the 5V Spartan family. Boundary scan logic is not usable during Power Down.

Configuration and Test

Configuration is the process of loading design-specific programming data into one or more FPGAs to define the functional operation of the internal blocks and their interconnections. This is somewhat like loading the command registers of a programmable peripheral chip. Spartan/XL devices use several hundred bits of configuration data per CLB and its associated interconnects. Each configuration bit defines the state of a static memory cell that controls either a function look-up table bit, a multiplexer input, or an interconnect pass transistor. The Xilinx development system translates the design into a netlist file. It automatically partitions, places and routes the logic and generates the configuration data in PROM format.

Configuration Mode Control

5V Spartan devices have two configuration modes.

- MODE = 1 sets Slave Serial mode
- MODE = 0 sets Master Serial mode

3V Spartan-XL devices have three configuration modes.

- M1/M0 = 11 sets Slave Serial mode
- M1/M0 = 10 sets Master Serial mode
- M1/M0 = 0X sets Express mode

In addition to these modes, the device can be configured through the Boundary Scan logic (See "Configuration Through the Boundary Scan Pins" on page 37.).

The Mode pins are sampled prior to starting configuration to determine the configuration mode. After configuration, these pin are unused. The Mode pins have a weak pull-up resistor turned on during configuration. With the Mode pins High, Slave Serial mode is selected, which is the most popular configuration mode. Therefore, for the most common configuration mode, the Mode pins can be left unconnected. If the Master Serial mode is desired, the MODE/M0 pin should be connected directly to GND, or through a pull-down resistor of 1 KΩ or less.

During configuration, some of the I/O pins are used temporarily for the configuration process. All pins used during con-

Slave Serial is the default mode if the Mode pins are left unconnected, as they have weak pull-up resistors during configuration.

Multiple slave devices with identical configurations can be wired with parallel DIN inputs. In this way, multiple devices can be configured simultaneously.

Serial Daisy Chain

Multiple devices with different configurations can be connected together in a "daisy chain," and a single combined bitstream used to configure the chain of slave devices.

To configure a daisy chain of devices, wire the CCLK pins of all devices in parallel, as shown in Figure 25. Connect the DOUT of each device to the DIN of the next. The lead or master FPGA and following slaves each passes resynchronized configuration data coming from a single source. The header data, including the length count, is passed through and is captured by each FPGA when it recognizes the 0010 preamble. Following the length-count data, each FPGA outputs a High on DOUT until it has received its required number of data frames.

After an FPGA has received its configuration data, it passes on any additional frame start bits and configuration data on DOUT. When the total number of configuration clocks applied after memory initialization equals the value of the 24-bit length count, the FPGAs begin the start-up sequence and become operational together. FPGA I/O are normally released two CCLK cycles after the last configuration bit is received.

The daisy-chained bitstream is not simply a concatenation of the individual bitstreams. The PROM File Formatter must be used to combine the bitstreams for a daisy-chained configuration.

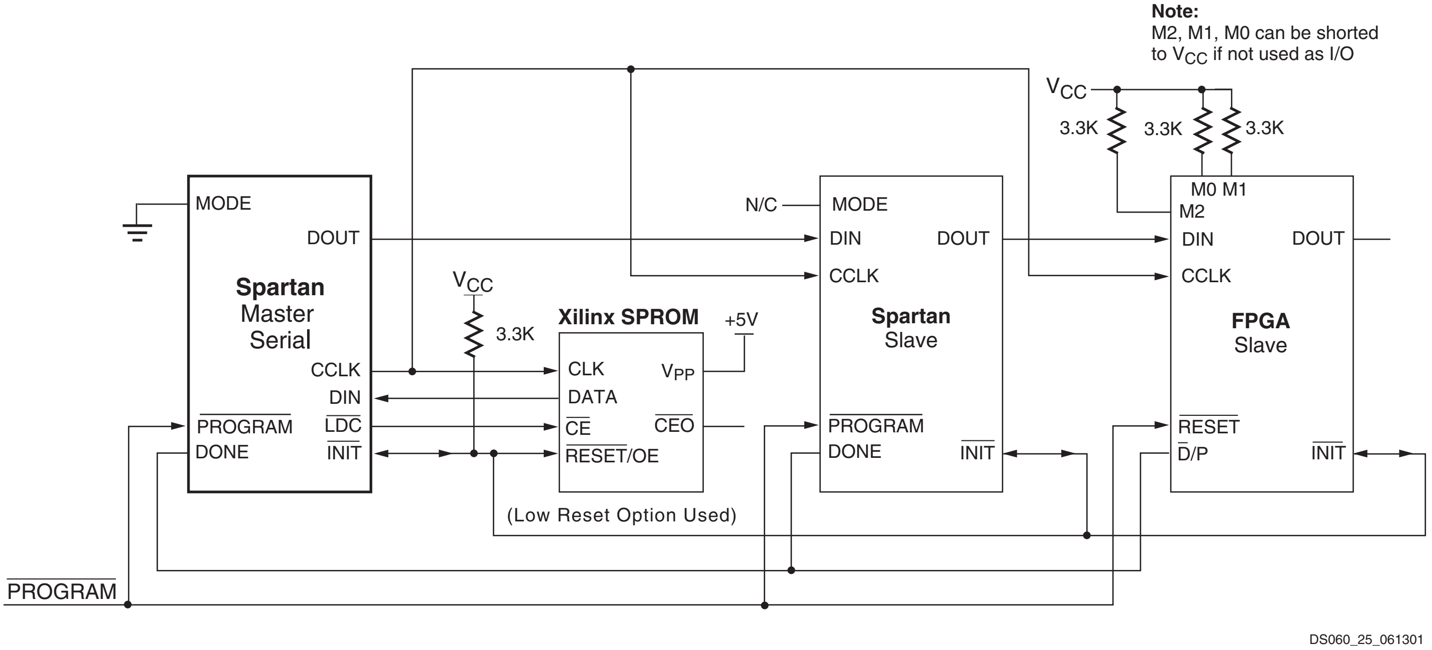


Figure 25: **Master/Slave Serial Mode Circuit Diagram**

Table 16: **Spartan/XL Data Stream Formats**

Data Type	Serial Modes (D0...)	Express Mode (D0-D7) (Spartan-XL only)
Fill Byte	11111111b	FFFFh
Preamble Code	0010b	11110010b
Length Count	COUNT[23:0]	COUNT[23:0][1]
Fill Bits	1111b	-
Field Check Code	-	11010010b
Start Field	0b	11111110b[2]
Data Frame	DATA[n–1:0]	DATA[n–1:0]
CRC or Constant Field Check	xxxx (CRC) or 0110b	11010010b
Extend Write Cycle	-	FFD2FFFFFFh
Postamble	01111111b	-
Start-Up Bytes[3]	FFh	FFFFFFFFFFFFFFh

Legend:

Unshaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

Notes:

1. Not used by configuration logic.
2. 11111111b for XCS40XL only.
3. Development system may add more start-up bytes.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The Spartan-XL family Express mode only supports non-CRC error checking. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading before DONE goes High, and the pulling down of the $\overline{\text{INIT}}$ pin. In Master serial mode, CCLK continues to operate externally. The user must detect $\overline{\text{INIT}}$ and initialize a new configuration by pulsing the $\overline{\text{PROGRAM}}$ pin Low or cycling V_{CC}.

Cyclic Redundancy Check (CRC) for Configuration and Readback

The Cyclic Redundancy Check is a method of error detection in data transmission applications. Generally, the transmitting system performs a calculation on the serial bitstream. The result of this calculation is tagged onto the data stream as additional check bits. The receiving system performs an identical calculation on the bitstream and compares the result with the received checksum.

Each data frame of the configuration bitstream has four error bits at the end, as shown in Table 16. If a frame data error is detected during the loading of the FPGA, the configuration process with a potentially corrupted bitstream is terminated. The FPGA pulls the $\overline{\text{INIT}}$ pin Low and goes into a Wait state.

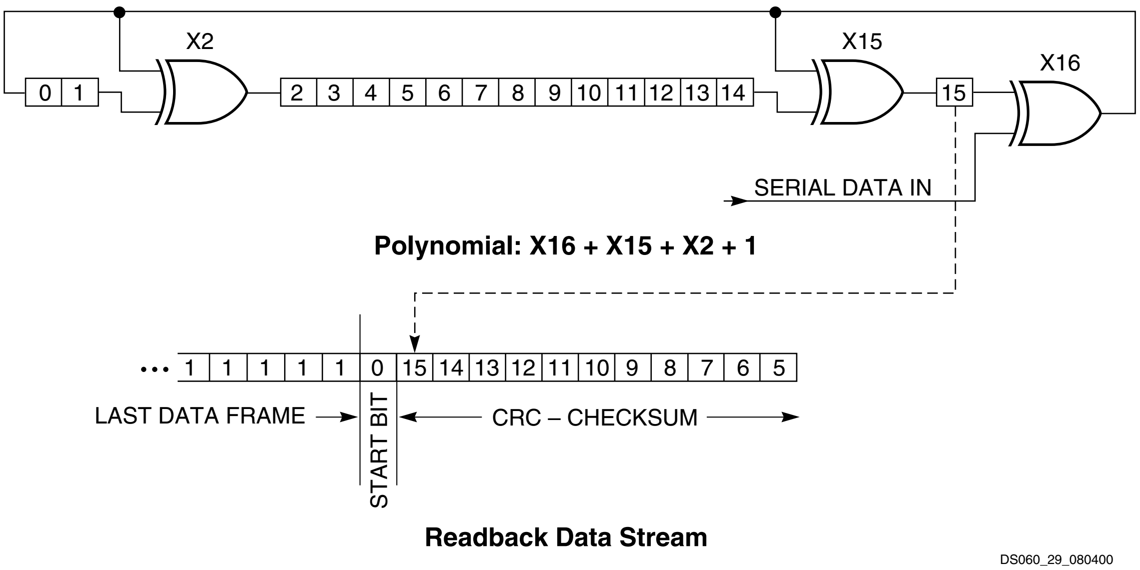


Figure 29: **Circuit for Generating CRC-16**

Configuration Sequence

There are four major steps in the Spartan/XL FPGA power-up configuration sequence.

- Configuration Memory Clear
- Initialization
- Configuration
- Start-up

The full process is illustrated in Figure 30.

Configuration Memory Clear

When power is first applied or is reapplied to an FPGA, an internal circuit forces initialization of the configuration logic. When V_{CC} reaches an operational level, and the circuit passes the write and read test of a sample pair of configuration bits, a time delay is started. This time delay is nominally 16 ms. The delay is four times as long when in Master Serial Mode to allow ample time for all slaves to reach a stable V_{CC}. When all $\overline{\text{INIT}}$ pins are tied together, as recommended, the longest delay takes precedence. Therefore, devices with different time delays can easily be mixed and matched in a daisy chain.

This delay is applied only on power-up. It is not applied when reconfiguring an FPGA by pulsing the $\overline{\text{PROGRAM}}$ pin Low. During this time delay, or as long as the $\overline{\text{PROGRAM}}$ input is asserted, the configuration logic is held in a Configuration Memory Clear state. The configuration-memory frames are consecutively initialized, using the internal oscillator.

At the end of each complete pass through the frame addressing, the power-on time-out delay circuitry and the level of the $\overline{\text{PROGRAM}}$ pin are tested. If neither is asserted, the logic initiates one additional clearing of the configuration frames and then tests the $\overline{\text{INIT}}$ input.

Initialization

During initialization and configuration, user pins HDC, $\overline{\text{LDC}}$, $\overline{\text{INIT}}$ and DONE provide status outputs for the system interface. The outputs $\overline{\text{LDC}}$, $\overline{\text{INIT}}$ and DONE are held Low and HDC is held High starting at the initial application of power.

The open drain $\overline{\text{INIT}}$ pin is released after the final initialization pass through the frame addresses. There is a deliberate delay before a Master-mode device recognizes an inactive $\overline{\text{INIT}}$. Two internal clocks after the $\overline{\text{INIT}}$ pin is recognized as High, the device samples the MODE pin to determine the configuration mode. The appropriate interface lines become active and the configuration preamble and data can be loaded.

Readback Switching Characteristics Guidelines

The following guidelines reflect worst-case values over the recommended operating conditions.

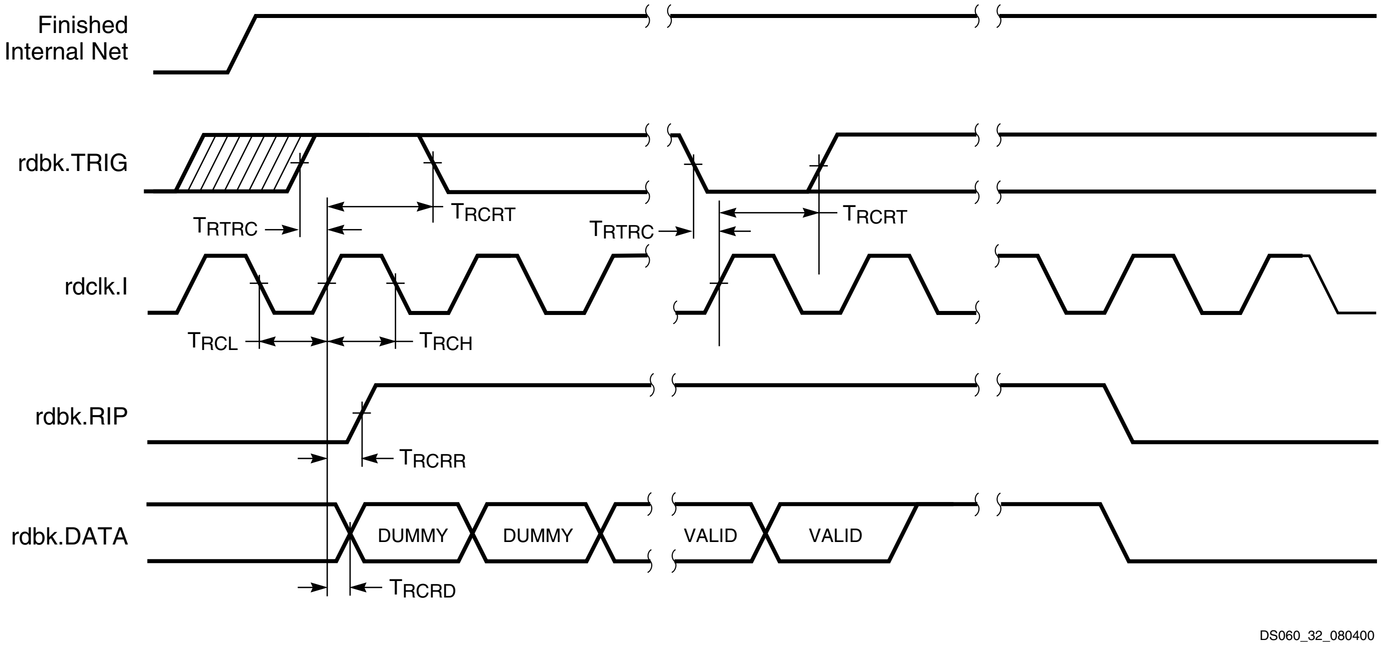


Figure 33: **Spartan and Spartan-XL Readback Timing Diagram**

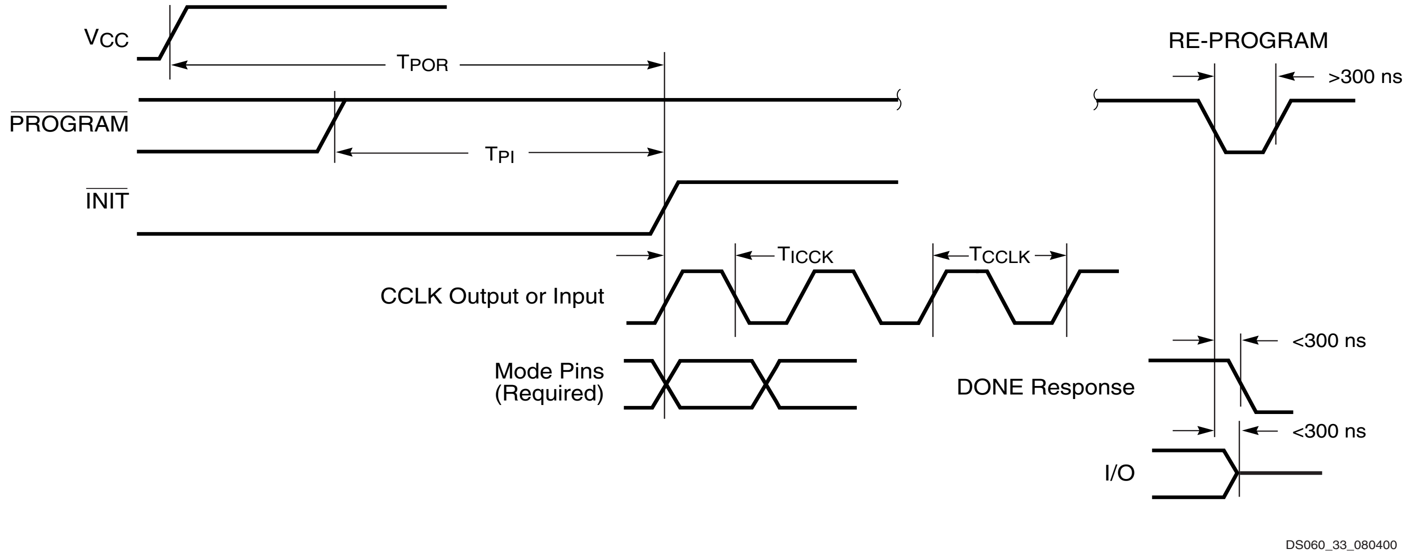
Spartan and Spartan-XL Readback Switching Characteristics

Symbol		Description	Min	Max	Units
T_{RTRC}	rdbk.TRIG	rdbk.TRIG setup to initiate and abort Readback	200	-	ns
T_{RCRT}		rdbk.TRIG hold to initiate and abort Readback	50	-	ns
T_{RCRD}	rdclk.I	rdbk.DATA delay	-	250	ns
T_{RCRR}		rdbk.RIP delay	-	250	ns
T_{RCH}		High time	250	500	ns
T_{RCL}		Low time	250	500	ns

Notes:

1. Timing parameters apply to all speed grades.
2. If rdbk.TRIG is High prior to Finished, Finished will trigger the first Readback.

Configuration Switching Characteristics



Master Mode

Symbol	Description	Min	Max	Units
T_{POR}	Power-on reset	40	130	ms
T_{PI}	Program Latency	30	200	µs per CLB column
T_{ICCK}	CCLK (output) delay	40	250	µs
T_{CCLK}	CCLK (output) period, slow	640	2000	ns
T_{CCLK}	CCLK (output) period, fast	100	250	ns

Slave Mode

Symbol	Description	Min	Max	Units
T_{POR}	Power-on reset	10	33	ms
T_{PI}	Program latency	30	200	µs per CLB column
T_{ICCK}	CCLK (input) delay (required)	4	-	µs
T_{CCLK}	CCLK (input) period (required)	80	-	ns

Spartan Family CLB Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and expressed in nanoseconds unless otherwise noted.

Symbol	Description	Speed Grade -4 Min	Speed Grade -4 Max	Speed Grade -3 Min	Speed Grade -3 Max	Units
Clocks						
T_{CH}	Clock High time	3.0	-	4.0	-	ns
T_{CL}	Clock Low time	3.0	-	4.0	-	ns
Combinatorial Delays						
T_{ILO}	F/G inputs to X/Y outputs	-	1.2	-	1.6	ns
T_{IHO}	F/G inputs via H to X/Y outputs	-	2.0	-	2.7	ns
T_{HH1O}	C inputs via H1 via H to X/Y outputs	-	1.7	-	2.2	ns
CLB Fast Carry Logic						
T_{OPCY}	Operand inputs (F1, F2, G1, G4) to C_{OUT}	-	1.7	-	2.1	ns
T_{ASCY}	Add/Subtract input (F3) to C_{OUT}	-	2.8	-	3.7	ns
T_{INCY}	Initialization inputs (F1, F3) to C_{OUT}	-	1.2	-	1.4	ns
T_{SUM}	C_{IN} through function generators to X/Y outputs	-	2.0	-	2.6	ns
T_{BYP}	C_{IN} to C_{OUT}, bypass function generators	-	0.5	-	0.6	ns
Sequential Delays						
T_{CKO}	Clock K to Flip-Flop outputs Q	-	2.1	-	2.8	ns
Setup Time before Clock K						
T_{ICK}	F/G inputs	1.8	-	2.4	-	ns
T_{IHCK}	F/G inputs via H	2.9	-	3.9	-	ns
T_{HH1CK}	C inputs via H1 through H	2.3	-	3.3	-	ns
T_{DICK}	C inputs via DIN	1.3	-	2.0	-	ns
T_{ECCK}	C inputs via EC	2.0	-	2.6	-	ns
T_{RCK}	C inputs via S/R, going Low (inactive)	2.5	-	4.0	-	ns
Hold Time after Clock K						
	All Hold times, all devices	0.0	-	0.0	-	ns
Set/Reset Direct						
T_{RPW}	Width (High)	3.0	-	4.0	-	ns
T_{RIO}	Delay from C inputs via S/R, going High to Q	-	3.0	-	4.0	ns
Global Set/Reset						
T_{MRW}	Minimum GSR pulse width	11.5	-	13.5	-	ns
T_{MRQ}	Delay from GSR input to any Q	See page 50 for T_{RRI} values per device.				
F_{TOG}	Toggle Frequency (MHz) (for export control purposes)	-	166	-	125	MHz

Spartan Family Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report.

Spartan Family Output Flip-Flop, Clock-to-Out

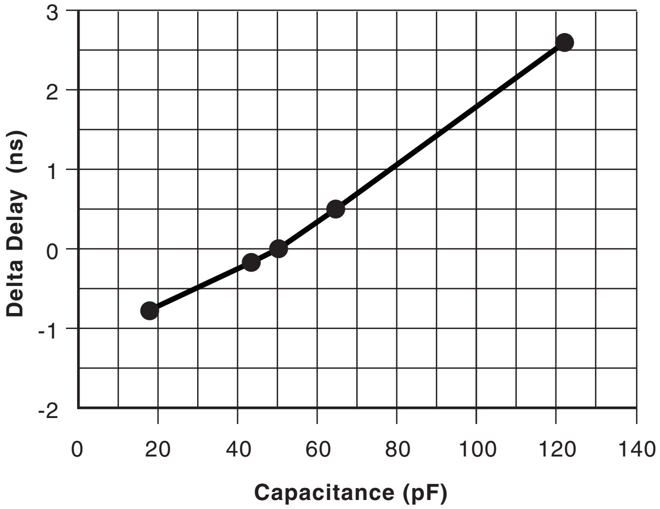
Symbol	Description	Device	Speed Grade -4 Max	Speed Grade -3 Max	Units
Global Primary Clock to TTL Output using OFF					
T_{ICKOF}	Fast	XCS05	5.3	8.7	ns
		XCS10	5.7	9.1	ns
		XCS20	6.1	9.3	ns
		XCS30	6.5	9.4	ns
		XCS40	6.8	10.2	ns
T_{ICKO}	Slew-rate limited	XCS05	9.0	11.5	ns
		XCS10	9.4	12.0	ns
		XCS20	9.8	12.2	ns
		XCS30	10.2	12.8	ns
		XCS40	10.5	12.8	ns
Global Secondary Clock to TTL Output using OFF					
T_{ICKSOF}	Fast	XCS05	5.8	9.2	ns
		XCS10	6.2	9.6	ns
		XCS20	6.6	9.8	ns
		XCS30	7.0	9.9	ns
		XCS40	7.3	10.7	ns
T_{ICKSO}	Slew-rate limited	XCS05	9.5	12.0	ns
		XCS10	9.9	12.5	ns
		XCS20	10.3	12.7	ns
		XCS30	10.7	13.2	ns
		XCS40	11.0	14.3	ns
Delay Adder for CMOS Outputs Option					
T_{CMOSOF}	Fast	All devices	0.8	1.0	ns
T_{CMOSO}	Slew-rate limited	All devices	1.5	2.0	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column,and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at ~50% V_{CC} threshold with 50 pF external capacitive load. For different loads, see Figure 34.
3. OFF = Output Flip-Flop

Capacitive Load Factor

Figure 34 shows the relationship between I/O output delay and load capacitance. It allows a user to adjust the specified output delay if the load capacitance is different than 50 pF. For example, if the actual load capacitance is 120 pF, add 2.5 ns to the specified delay. If the load capacitance is 20 pF, subtract 0.8 ns from the specified output delay. Figure 34 is usable over the specified operating conditions of voltage and temperature and is independent of the output slew rate control.



DS060_35_080400

Figure 34: **Delay Factor at Various Capacitive Loads**

Spartan-XL Family DC Characteristics Over Operating Conditions

Symbol	Description		Min	Typ.	Max	Units
V_{OH}	High-level output voltage @ $I_{OH} = –4.0$ mA, V_{CC} min (LVTTL)		2.4	-	-	V
	High-level output voltage @ $I_{OH} = –500$ µA, (LVCMOS)		90% V_{CC}	-	-	V
V_{OL}	Low-level output voltage @ $I_{OL} = 12.0$ mA, V_{CC} min (LVTTL)(1)		-	-	0.4	V
	Low-level output voltage @ $I_{OL} = 24.0$ mA, V_{CC} min (LVTTL)(2)		-	-	0.4	V
	Low-level output voltage @ $I_{OL} = 1500$ µA, (LVCMOS)		-	-	10% V_{CC}	V
V_{DR}	Data retention supply voltage (below which configuration data may be lost)		2.5	-	-	V
I_{CCO}	Quiescent FPGA supply current(3,4)	Commercial	-	0.1	2.5	mA
		Industrial	-	0.1	5	mA
I_{CCPD}	Power Down FPGA supply current(3,5)	Commercial	-	0.1	2.5	mA
		Industrial	-	0.1	5	mA
I_L	Input or output leakage current		–10	-	10	µA
C_{IN}	Input capacitance (sample tested)		-	-	10	pF
I_{RPU}	Pad pull-up (when selected) @ $V_{IN} = 0V$ (sample tested)		0.02	-	0.25	mA
I_{RPD}	Pad pull-down (when selected) @ $V_{IN} = 3.3V$ (sample tested)		0.02	-	-	mA

Notes:
1. With up to 64 pins simultaneously sinking 12 mA (default mode).
2. With up to 64 pins simultaneously sinking 24 mA (with 24 mA option selected).
3. With 5V tolerance not selected, no internal oscillators, and the FPGA configured with the Tie option.
4. With no output current loads, no active input resistors, and all package pins at V_{CC} or GND.
5. With $\overline{\text{PWRDWN}}$ active.

Supply Current Requirements During Power-On

Spartan-XL FPGAs require that a minimum supply current I_{CCPO} be provided to the V_{CC} lines for a successful power on. If more current is available, the FPGA can consume more than I_{CCPO} min., though this cannot adversely affect reliability.

A maximum limit for I_{CCPO} is not specified. Be careful when using foldback/crowbar supplies and fuses. It is possible to control the magnitude of I_{CCPO} by limiting the supply current available to the FPGA. A current limit below the trip level will avoid inadvertently activating over-current protection circuits.

Symbol	Description	Min	Max	Units
I_{CCPO}	Total V_{CC} supply current required during power-on	100	-	mA
T_{CCPO}	V_{CC} ramp time(2,3)	-	50	ms

Notes:
1. The I_{CCPO} requirement applies for a brief time (commonly only a few milliseconds) when V_{CC} ramps from 0 to 3.3V.
2. The ramp time is measured from GND to V_{CC} max on a fully loaded board.
3. V_{CC} must not dip in the negative direction during power on.

Spartan-XL Family Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

Spartan-XL Family Output Flip-Flop, Clock-to-Out

Symbol	Description	Device	Speed Grade -5 Max	Speed Grade -4 Max	Units
Global Clock to Output using OFF					
T_{ICKOF}	Fast	XCS05XL	4.6	5.2	ns
		XCS10XL	4.9	5.5	ns
		XCS20XL	5.2	5.8	ns
		XCS30XL	5.5	6.2	ns
		XCS40XL	5.8	6.5	ns
Slew Rate Adjustment					
T_{SLOW}	For Output SLOW option add	All Devices	1.5	1.7	ns

Notes:

1. Output delays are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at ~50% V_{CC} threshold with 50 pF external capacitive load.
3. OFF = Output Flip Flop

Spartan-XL Family IOB Input Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade				Units
			-5		-4		
			Min	Max	Min	Max	
Setup Times							
T_{ECIK}	Clock Enable (EC) to Clock (IK)	All devices	0.0	-	0.0	-	ns
T_{PICK}	Pad to Clock (IK), no delay	All devices	1.0	-	1.2	-	ns
T_{POCK}	Pad to Fast Capture Latch Enable (OK), no delay	All devices	0.7	-	0.8	-	ns
Hold Times							
	All Hold Times	All devices	0.0	-	0.0	-	ns
Propagation Delays							
T_{PID}	Pad to I1, I2	All devices	-	0.9	-	1.1	ns
T_{PLI}	Pad to I1, I2 via transparent input latch, no delay	All devices	-	2.1	-	2.5	ns
T_{IKRI}	Clock (IK) to I1, I2 (flip-flop)	All devices	-	1.0	-	1.1	ns
T_{IKLI}	Clock (IK) to I1, I2 (latch enable, active Low)	All devices	-	1.1	-	1.2	ns
Delay Adder for Input with Full Delay Option							
T_{Delay}	$T_{PICKD} = T_{PICK} + T_{Delay}$ $T_{PDLI} = T_{PLI} + T_{Delay}$	XCS05XL	4.0	-	4.7	-	ns
		XCS10XL	4.8	-	5.6	-	ns
		XCS20XL	5.0	-	5.9	-	ns
		XCS30XL	5.5	-	6.5	-	ns
		XCS40XL	6.5	-	7.6	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns
T_{RRI}	Delay from GSR input to any Q	XCS05XL	-	9.0	-	10.5	ns
		XCS10XL	-	9.5	-	11.0	ns
		XCS20XL	-	10.0	-	11.5	ns
		XCS30XL	-	11.0	-	12.5	ns
		XCS40XL	-	12.0	-	13.5	ns

Notes:

1. Input pad setup and hold times are specified with respect to the internal clock (IK). For setup and hold times with respect to the clock input, see the pin-to-pin parameters in the Pin-to-Pin Input Parameters table.
2. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

XCS30 and XCS30XL Device Pinouts *(Continued)*

XCS30/XL Pad Name	VQ100(5)	TQ144	PQ208	PQ240	BG256(5)	CS280(2,5)	Bndry Scan
I/O	-	-	-	P190	B16	A15	23
I/O	-	P117	P166	P191	A16	E14	26
I/O	-	-	P167	P192	C15	C14	29
I/O	-	-	P168	P193	B15	B14	32
I/O	-	-	P169	P194	A15	D14	35
GND	-	P118	P170	P196	GND(4)	GND(4)	-
I/O	-	P119	P171	P197	B14	A14	38
I/O	-	P120	P172	P198	A14	C13	41
I/O	-	-	-	P199	C13	B13	44
I/O	-	-	-	P200	B13	A13	47
VCC	-	-	P173	P201	VCC(4)	D13	-
I/O	P82	P121	P174	P202	C12	B12	50
I/O	P83	P122	P175	P203	B12	D12	53
I/O	-	-	P176	P205	A12	A11	56
I/O	-	-	P177	P206	B11	B11	59
I/O	P84	P123	P178	P207	C11	C11	62
I/O	P85	P124	P179	P208	A11	D11	65
I/O	P86	P125	P180	P209	A10	A10	68
I/O	P87	P126	P181	P210	B10	B10	71
GND	P88	P127	P182	P211	GND(4)	GND(4)	-

2/8/00

Notes:

1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The “PWRDWN” on the XCS30XL is not part of the Boundary Scan chain. For the XCS30XL, subtract 1 from all Boundary Scan numbers from GCK3 on (295 and higher).
4. Pads labeled GND(4) or V_{CC}(4) are internally bonded to Ground or V_{CC} planes within the package.
5. CS280 package, and VQ100 and BG256 packages for XCS30 only, discontinued by PDN2004-01

Additional XCS30/XL Package Pins

PQ240

GND Pins					
P22	P37	P83	P98	P143	P158
P204	P219	-	-	-	-
Not Connected Pins					
P195	-	-	-	-	-

2/12/98

BG256

VCC Pins					
C14	D6	D7	D11	D14	D15
E20	F1	F4	F17	G4	G17
K4	L17	P4	P17	P19	R2
R4	R17	U6	U7	U10	U14
U15	V7	W20	-	-	-

GND Pins					
A1	B7	D4	D8	D13	D17
G20	H4	H17	N3	N4	N17
U4	U8	U13	U17	W14	-
Not Connected Pins					
A7	A13	C8	D12	H20	J3
J4	M4	M19	V9	W9	W13
Y13	-	-	-	-	-

6/4/97

CS280

VCC Pins					
A1	A7	C10	C17	D13	G1
G1	G19	K2	K17	M4	N16
T7	U3	U10	U17	W13	-
GND Pins					

Product Availability

Table 19 shows the packages and speed grades for Spartan/XL devices. Table 20 shows the number of user I/Os available for each device/package combination.

Table 19: **Component Availability Chart for Spartan/XL FPGAs**

Device	Pins	84	100	144	144	208	240	256	280
	Type	Plastic PLCC	Plastic VQFP	Chip Scale	Plastic TQFP	Plastic PQFP	Plastic PQFP	Plastic BGA	Chip Scale
	Code	PC84(3)	VQ100(3)	CS144(3)	TQ144	PQ208	PQ240	BG256(3)	CS280(3)
XCS05	-3	C(3)	C, I	-	-	-	-	-	-
	-4	C(3)	C	-	-	-	-	-	-
XCS10	-3	C(3)	C, I	-	C	-	-	-	-
	-4	C(3)	C	-	C	-	-	-	-
XCS20	-3	-	C	-	C, I	C, I	-	-	-
	-4	-	C	-	C	C	-	-	-
XCS30	-3	-	C(3)	-	C, I	C, I	C	C(3)	-
	-4	-	C(3)	-	C	C	C	C(3)	-
XCS40	-3	-	-	-	-	C, I	C	C	-
	-4	-	-	-	-	C	C	C	-
XCS05XL	-4	C(3)	C, I	-	-	-	-	-	-
	-5	C(3)	C	-	-	-	-	-	-
XCS10XL	-4	C(3)	C, I	C(3)	C	-	-	-	-
	-5	C(3)	C	C(3)	C	-	-	-	-
XCS20XL	-4	-	C, I	C(3)	C, I	C, I	-	-	-
	-5	-	C	C(3)	C	C	-	-	-
XCS30XL	-4	-	C, I	-	C, I	C, I	C	C	C(3)
	-5	-	C	-	C	C	C	C	C(3)
XCS40XL	-4	-	-	-	-	C, I	C	C, I	C(3)
	-5	-	-	-	-	C	C	C	C(3)

6/25/08

Notes:
1. C = Commercial T_J = 0° to +85°C
2. I = Industrial T_J = –40°C to +100°C
3. PC84, CS144, and CS280 packages, and VQ100 and BG256 packages for XCS30 only, discontinued by **PDN2004-01**
4. Some Spartan-XL devices are available in Pb-free package options. The Pb-free packages insert a "G" in the package code. Contact Xilinx for availability.

Package Specifications

Package drawings and material declaration data sheets for the Spartan/XL devices can be found on the Xilinx website at:

www.xilinx.com/support/documentation/spartan-xl.htm#19687

Thermal data for the Spartan/XL packages can be found using the thermal query tool on the Xilinx website at:

www.xilinx.com/cgi-bin/thermal/thermal.pl